## Search Notes



403.1

218.1

413

204

429

205

Application/Control No.	Applicant(s)/Patent Under Reexamination
09996120	CHAN ET AL.
Examiner	Art Unit
EDNA WONG	1795

6/16/06

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4/9/08

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SEARCHED							
Class	Subclass	Date	Examiner				
568	959	6/16/06	EW				
205	343	6/16/06	EW				
205	427	6/16/06	EW				
205	455	6/16/06	EW				
205	293	6/16/06	EW				

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventor Search	6/16/06	EW		
EAST	6/16/06	EW		
Search Updated	12/29/06	EW		
EAST	12/29/06	EW		
Search Updated	3/29/07	EW		
STN	3/29/07	EW		
Search Updated	6/2/07	EW		
Search Updated	12/26/07	EW		
Search Updated	4/9/08	EW		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
205	343	4/12/08	EW		
205	427	4/12/08	EW		
205	455	4/12/08	EW		
205	413	4/12/08	EW		

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